

Test and Experimental Facilities

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Test Experiment/Facilities

	Level of Need	Availability	Level of Maturity	Timeline/costs	Inter-dependencies
Machinery	H	M	M-	2 yrs & Low	Y algorithms
Electronic	H	L	L	Now & High	Y algorithms/data
Structures	H	M-	L+	Now & High	Y algorithms/sensors
Integration	H+	L	L	Now & Med	Y algorithms/data

COE Role

- Prognostics for electronics
- False alarms
- Run to failure
- Methodologies for “affordable” tests
- Physics of failure and feature extractions for end of life predictions
- Intelligent Integration
- Produce data and help map prognostic plane
- Evaluate technologies

Existing Test Facilities

- NASA
- DoD
- DoE
- Universities/MURI
- OEM's
- Depots
- CALCE
- DoT